## Search Notes



## Application/Control No.

10531753

Applicant(s)/Patent Under Reexamination

NESZ ET AL.

Examiner

Art Unit

SHAQ TAHA

2478

## SEARCHED

Class	Subclass	Date	Examiner
10	227	10/16/2008	S. Taha
709	227	03/25/2009	S. Taha
709	227	12/20/2009	S. Taha
709	227	09/02/2010	S. Taha
709	227	04/0/20114	S. Taha

SEARCH	NOTES

Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see	09/10/2008	S. Taha
attached; NPL: IEEE; Inventor Search/DP; Text search in cls		
709/223,224,225,226,228,229		
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see	03/25/2009	S. Taha
attached; NPL: IEEE; Inventor Search/DP; Text search in cls		
709/223,224,225,226,228,229		
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see	12/20/2009	S. Taha
attached; NPL: IEEE; Inventor Search/DP; Text search in cls		
709/223,224,225,226,228,229		
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see	09/02/2010	S. Taha
attached; NPL: IEEE; Inventor Search/DP; Text search in cls		1
709/223,224,225,226,228,229		
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see	04/0/20114	S. Taha
attached; NPL: IEEE; Inventor Search/DP; Text search in cls		
709/223,224,225,226,228,229	1	1

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
PG Pub	see attached history	04/01/2011	S. Taha

/S. T./

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